k-Space Associates, Inc.

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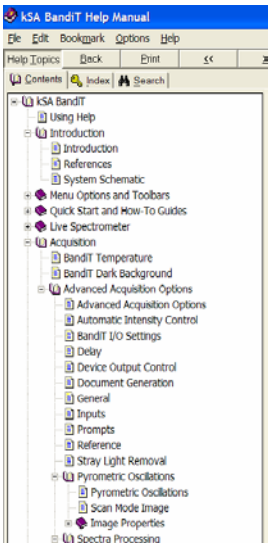
New k-Space Application Notes

k-Space Associates wants to share recent application data as well as how kSA customers are using our products. We will be distributing new Application Notes via our newsletter list, beginning with use of kSA BandiT for GaN temperature monitoring (a PDF copy is attached to this newsletter mailing).

Summer Sale – 15% off kSA 400 Upgrades!

The kSA 400 analytical RHEED system instantly puts the power of RHEED at your fingertips! Continued product development over the past 13 years has created today's most powerful analytical RHEED system. k-Space strives to stay ahead of the pack and we would like to make it just a bit easier for you to obtain the most current capabilities the kSA 400 has to offer. Now through August 15th, save 15% on all kSA 400 upgrades for systems sold prior to June 2004. Please contact k-Space or your local representative for more details.

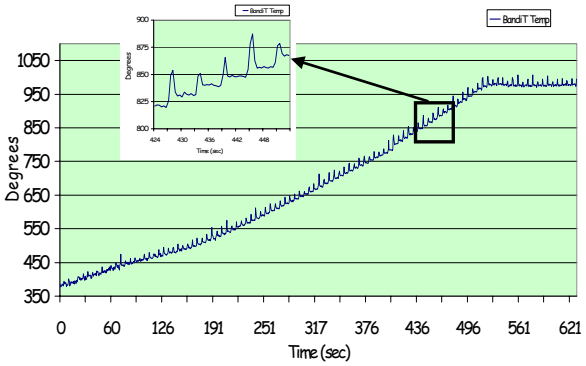
Tech Tips – New kSA BandiT User HELP Manual



Having shipped our 25th kSA BandiT system, k-Space is pleased to announce our latest version of the BandiT Help Manual. This complete, exhaustive, context-sensitive document compiles many of the most common questions and operational tips to help you make the most of BandiT's extensive capabilities. Simple, Windows-based searching and links make finding answers to your questions easy. The manual is also available in html format, and can be easily printed for hard copy reference. Of course, k-Space's engineers are always available with unlimited, free technical support. BandiT users will receive their copy via email within the next two weeks.

New "Naked" kSA 400 Flange Mount

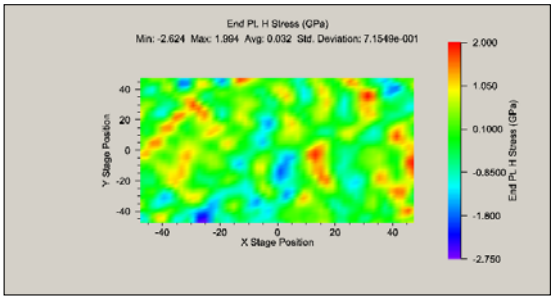
While our standard kSA 400 flange mounts keep the light out, that also means they take up additional space to enclose the camera. So for those who have systems with tighter quarters, we now have a "naked" mount featuring stainless steel rails for camera support. Let us know if you'd like a quote for your system!



New kSA BandiT Results for MOCVD GaN Temperature Measurement!

k-Space has just completed GaN on sapphire film (not the susceptor!) temperature testing on the Aixtron G2 MOCVD reactor, and the results are excellent! The figure above shows kSA BandiT data during a temperature ramp. Note that the apparent noise in the data is not noise at all, but rather variations in temperature between wafers (see inset). The data taken shows approximately 12 temperature measurements per wafer, yielding never before seen spatially-resolved GaN film temperature measurement. Validated for both MBE and MOCVD, the GaN BandiT is a powerful tool for measuring true wafer surface temperature without the limitations of currently available techniques.

kSA MOS Ultra Scan For Dielectric Thin Film Stress Mapping



Introduced just six months ago, the kSA MOS Ultra Scan is busy running thin film stress samples for numerous advanced semiconductor and optical coating applications. Shown above is a sample 2D mapping of induced thin film dielectric stress on silicon. The test was performed by first mapping a bare silicon substrate and then re-mapping after subsequent deposition of a SiN_3 thin film. Ultra Scan's patented 2D laser array - used for determining curvature and induced stress - ensures resolution and repeatability, unmatched by any other technique.

k-Space Announces New Distributor in Asia Pacific

k-Space is pleased to announce that Teltec Semiconductor Pacific (www.teltec.biz) will be representing the k-Space product line in Taiwan, China, Hong Kong, and Singapore-Malaysia. For over 20 years, Teltec has specialized in serving the advanced semiconductor community in technical expertise and customer service.

k-Space Associates, Inc., 3626 W. Liberty Rd., Ann Arbor, MI 48103 USA
Tel: (734) 668-4644 • Fax: (734) 668-4663
requestinfo@k-space.com • www.k-space.com